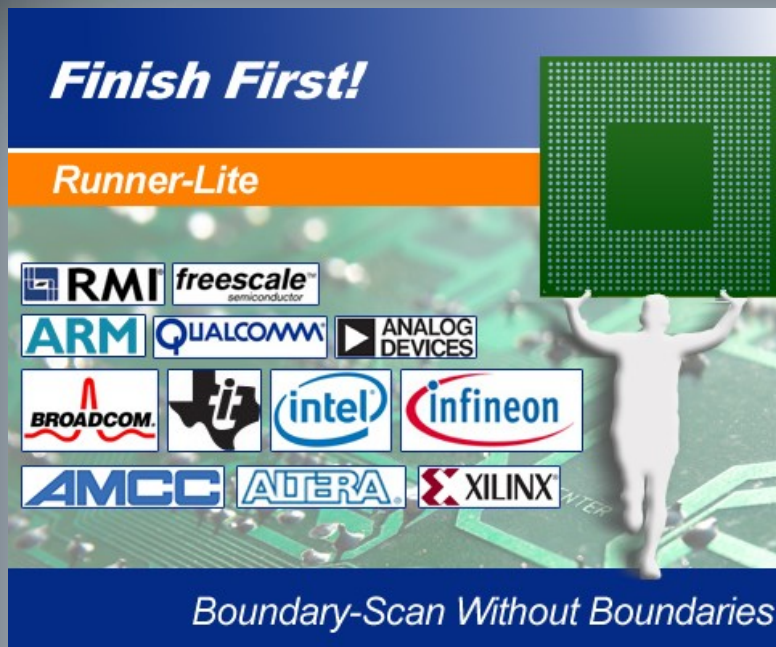


# Runner-Lite

**CORELIS**  
An EWA Company

Out-of-the-Box Structural and Functional Test Solutions

Preferred Boundary-Scan Solutions—Acclaimed Technical Support



**Finish First!**

Runner-Lite

RMI freescale semiconductor  
ARM QUALCOMM ANALOG DEVICES  
BROADCOM ti intel infineon  
AMCC ALTERA XILINX

Boundary-Scan Without Boundaries

The graphic features a central image of a person in a white suit running on a green circuit board. Above the person is a large green square with a grid pattern. The text 'Finish First!' is in a blue banner at the top left, 'Runner-Lite' is in an orange banner below it, and 'Boundary-Scan Without Boundaries' is in a blue banner at the bottom. Logos for various semiconductor companies are arranged in a grid around the central image.

## Main Features

- Built-in test sequencer that automatically executes independent test steps
- Executes structural and functional board tests via a simple JTAG connection
- Complete ready-to-run reference design test procedures
- Detects and isolates faults down to the net and pin level
- Easy-to-use graphical user interface
- Programs Flash & other programmable devices
- Integrated Advanced Diagnostics (ADO) provides detailed fault report logs and proximity diagnostics

Embedded product design is difficult enough—having to thoroughly test the design adds a whole new level of complexity. Wouldn't it be nice if a comprehensive test procedure was available before your first article design was ready?

Look no further. Runner-Lite is Corelis' answer to complete off-the-shelf JTAG structural and functional test solutions for the most popular silicon vendor reference designs available today. If you're new to JTAG or have been hesitant to implement this test technology, let Runner-Lite put printed circuit board (PCB) test convenience into your hands.

Getting started using JTAG has never been easier. Best of all...it's FREE!

## Applications

- **JTAG Education**—Discover how to perform JTAG structural and functional testing on your design
- **Prototype Development and Debug**—Instantly pin-point PCB failures and isolate manufacturing defects

## Benefits

- Fully working test procedures means zero test development time
- Find faults before any application code is ready
- Spend less time debugging hardware problems
- Rapidly release prototypes
- Speed diagnosis and repair of faulty circuit boards

**Learn More:** For more information about Corelis products, please visit [www.corelis.com](http://www.corelis.com)

Runner-Lite includes a powerful graphical fault identification subsystem that helps isolate the location of PCB faults. The tool provides design and test engineers with the ability to visually analyze fault diagnostic data on a physical PCB display. Runner-Lite is able to depict a CAD-based photographic representation of a reference design to facilitate the rapid discovery and actual location of any failure, even when they are hidden underneath devices.

Runner-Lite offers peace of mind when a board passes its comprehensive testing. It further relieves stress by revealing fault locations. Download the free Runner-Lite software package today to see faults like you've never seen them before.



Runner-Lite - TI-OMAP3530 EVM Rev D.tsp

File Setup Run View Help

Test Steps:

#	Test Step Name	Results
1	JTAG_Controller_Reset.etf	Passed
2	JTAG_Mode_Initialization.svf	Passed
3	JTAG_Combined_infrastructure_inf.cvf	Passed
4	JTAG_Combined_interconnect_ic.cvf	Passed
5	JTAG_Combined_resistor_pull.cvf	Passed
6	Functional_mode.svf	Passed
7	Functional_Initialization.jet	Passed
8	Functional_RAM[U1]_Address_Bus_Test.jet	Passed
9	Functional_RAM[U1]_Data_Bus_Test.jet	Passed
10	Functional_RAM[U1]_Real_Time_Exhaustive_Test.jet	Passed
11	Functional_UART[U33]_Internal_Loopback_Test.jet	Passed
12	Functional_UART[U33]_External_Loopback_Test.jet	Passed
13	Functional_Flash[U1]_Initialization.jet	Passed
14	Functional_Flash[U1]_DeviceID_Check_Test.jet	Passed
15	Functional_EMAC[U22]_Internal_Loopback_Test.jet	Passed
16	Functional_EMAC[U22]_External_Loopback_Test.jet	Passed
17	Functional_I2C_Discovery_Test.jet	Passed
18	Functional_Audio_Test.jet	Passed
19	Functional_Display_LCD_Touchscreen_Test.jet	Passed
20	Functional_KeyPad[S4-S6]_Interactive_Test.jet	Passed
21	Functional_USB[U36]_Connection_Test.jet	Passed
22	Functional_SD_MMC_Connection_Test.jet	Passed

Test Status: Status **Ready**, Results **Passed**

Test Statistics: Total Runs 1, Passed Runs 1, Failed Runs 0

Run Test Close

100% Time: 00:02:14.5

## Additional Features

- Identifies PCB assembly faults using a photographic image superimposed on CAD data
- Identifies failures by fault type including stuck-at, open, and short
- Double-sided PCB support
- Powerful zoom, pan, auto-center, and filter functions
- Netlist & parts browser highlights component, pin, and via locations

## Download Information

<http://www.corelis.com/Runner-Lite>

## CORELIS

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